



Docket Number: 081468-0306518

PATENT APPLICATION

Client Reference: P-0365.010-US

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of

ARIE JEFFREY DEN BOEF, et al.

Group Art Unit: (Unknown)

Application No.: 10/696,742

Examiner: (Unknown)

Filed: October 30, 2003

Confirmation No.: (Unknown)

For: TEST PATTERN, INSPECTION METHOD, AND DEVICE MANUFACTURING METHOD

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P. O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR 1.56, the attention of the Patent and Trademark Office is hereby directed to the reference(s) listed on the attached PTO-1449s. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the reference(s) be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date of this non-CPA application. No certification or fee is required.

The reference(s) was/were cited in a counterpart foreign application. An English language version of the foreign search report is attached for the Examiner's information.

Respectfully Submitted,

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Atty. Dkt. No.	M#	Client Ref.
	0306518	P-0365.010-US

**INFORMATION DISCLOSURE STATEMENT  
BY APPLICANT**

Applicant: DEN BOEF et al.

Appln. No.: 10/696,742

Filing Date: October 30, 2003

Date: November 19, 2003 Page 1 of 1

Examiner: (Unknown) Group Art Unit:

**U.S. PATENT DOCUMENTS**

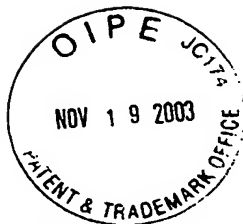
Examiner's Initials*		Document Number	Date MM/YY YY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
	AR	US-2002/0041373 A1	4/2002	LITTAU et al.			
	BR	6,458,605 B1	10/2002	STIRTON			
	CR						
	DR						
	ER						
	FR						
	GR						
	HR						
	IR						
	JR						
	KR						
	LR						
	MR						
	NR						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date MM/YYYY	Country	Inventor Name	English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
	OR	WO 03 001297 A	01/2003	PCT	MIEHER	X			
	PR	WO 02 077570 A	10/2002	PCT	SINGH et al.	X			
	QR	WO 02 21075 A	03/2002	PCT	LITTAU	X			
	RR	EP 0 985 977 A	03/2000	EPO	EICHNER et al.	X			
	SR	WO 02 070985 A	09/2002	PCT	RAYMOND	X			
	TR	WO 02 065545 A2	08/2002	PCT	SEZGINER	X			
	UR								
	VR								
	WR								
	XR								

Examiner Date Considered:

\*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.



PTO/SB/08b(05-03)

Approved for use through 04/30/2003. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE

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<b>Substitute for form 1449B/PTO</b>  <b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)		<b>Complete if Known</b>			
		Application Number	10/696,742		
		Filing Date	10/30/2003		
		First Named Inventor	ARIE JEFFREY DEN BOEF		
		Art Unit	0000		
		Examiner Name	(UNKNOWN)		
Sheet	1	of	1	Attorney Docket Number	081468-0306518

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>
	9	K.C. HICKMAN ET AL., "Use of Diffracted Light From Latent Images to Improve Lithography Control," Journal of Vacuum Science & Technology B, American Vacuum Society (USA), Vol. 10 ( No. 5), p. 2259-2266, ( Sept/Oct 1992).	
	10	E.L. RAAB ET AL., "Analyzing Deep-UV Lens Aberrations Using Aerial Image and Latent Image Metrologies," SPIE, SPIE (USA), 2-4 March, 1994, p. 550-565, (vol. 2197).	
	11	CHRISTOPHER J. RAYMOND ET AL., "Multiparameter Grating Metrology Using Optical Scatterometry," Journal of Vacuum Science & Technology B, 2nd ed., American Institute of Physics for the American Vacuum Society (USA), Vol. 15 ( No. 2), p. 361-368, ( Mar/Apr 1997).	
	12	XINHUI NIU ET AL., "Specular Spectroscopic Scatterometry in DUV Lithography," Part of the SPIE Conference on Metrology, Inspection, and Process Control for Microlithography XIII, SPIE (Santa Clara, CA, USA), p. 159-168, ( March 1999) (vol. 3677).	

Examiner Signature		Date Considered	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>1</sup> Applicant's unique citation designation number (optional). <sup>2</sup> Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CFR 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 120 minutes to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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